

| L Number | Hits | Search Text | DB | Time stamp |
|----------|-------|---|--------------------------|------------------|
| 1 | 40262 | (reference near3 potential) or (voltage near3 referece) | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:24 |
| 2 | 351 | measur\$5 near10 (data near3 potential) | USPAT; EPO; JPO; DERWENT | 2003/11/05 11:58 |
| 3 | 8 | measur\$5 same (data near3 potential) same (bit-line\$1 or BL\$1) | USPAT; EPO; JPO; DERWENT | 2003/11/05 11:59 |
| 4 | 98 | measur\$5 same potential same (bit-line\$1 or BL\$1) | USPAT; EPO; JPO; DERWENT | 2003/11/05 11:59 |
| 5 | 18 | measur\$5 same potential same (bit-line\$1 or BL\$1) same test\$3 | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:00 |
| 6 | 46 | (measur\$5 same potential same (bit-line\$1 or BL\$1)) and test\$3 | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:00 |
| 7 | 18 | ((measur\$5 near5 potential) same (bit-line\$1 or BL\$1)) and test\$3 | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:01 |
| 8 | 40245 | (reference near3 potential) | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:25 |
| 9 | 32789 | (reference near1 potential) | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:25 |
| 10 | 3201 | (reference adj1 potential) adj4 (device or circuit or means) | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:26 |
| 11 | 4 | ((reference adj1 potential) adj4 (device or circuit or means)) same tester | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:26 |
| 12 | 93 | ((reference adj1 potential) adj4 (device or circuit or means)) same test\$3 | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:27 |
| 13 | 457 | ((reference adj1 potential) adj4 (device or circuit or means)) and test\$3 | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:27 |
| 14 | 305 | ((reference adj1 potential) adj4 (device or circuit or means)) and test\$3 and amplif\$4 | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:27 |
| 15 | 167 | ((reference adj1 potential) adj2 (device or circuit or means)) and test\$3 and amplif\$4 | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:28 |
| 16 | 181 | ((reference adj1 potential) adj2 (device or circuit or means or generator)) and test\$3 and amplif\$4 | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:33 |
| 17 | 138 | ((reference adj1 potential) adj2 (device or circuit or means or generator)) and test\$3 and amplif\$4 and transistor | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:33 |
| 18 | 1 | ((reference adj1 potential) adj2 (device or circuit or means or generator)) and test\$3 and amplif\$4 and transistor and bit-lines and word-lines | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:33 |
| 19 | 2 | ((reference adj1 potential) adj2 (device or circuit or means or generator)) and test\$3 and amplif\$4 and transistor and bit-lines | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:34 |
| 20 | 3 | ((reference adj1 potential) adj2 (device or circuit or means or generator)) and test\$3 and amplif\$4 and bit-lines | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:35 |
| 21 | 76 | ((reference adj1 potential) adj2 (device or circuit or means or generator)) and test\$3 and amplif\$4 and ((bit adj1 lines) or bl\$2) | USPAT; EPO; JPO; DERWENT | 2003/11/05 12:35 |